



57th Annual Denver X-ray Conference

Denver, Colorado

DETERMINATION OF ACTIVATION ENERGY IN TEXTURED METAL-METAL MULTILAYER FILMS VIA 2D XRD

Mark A. Rodriguez, David P. Adams,
and Ralph G. Tissot

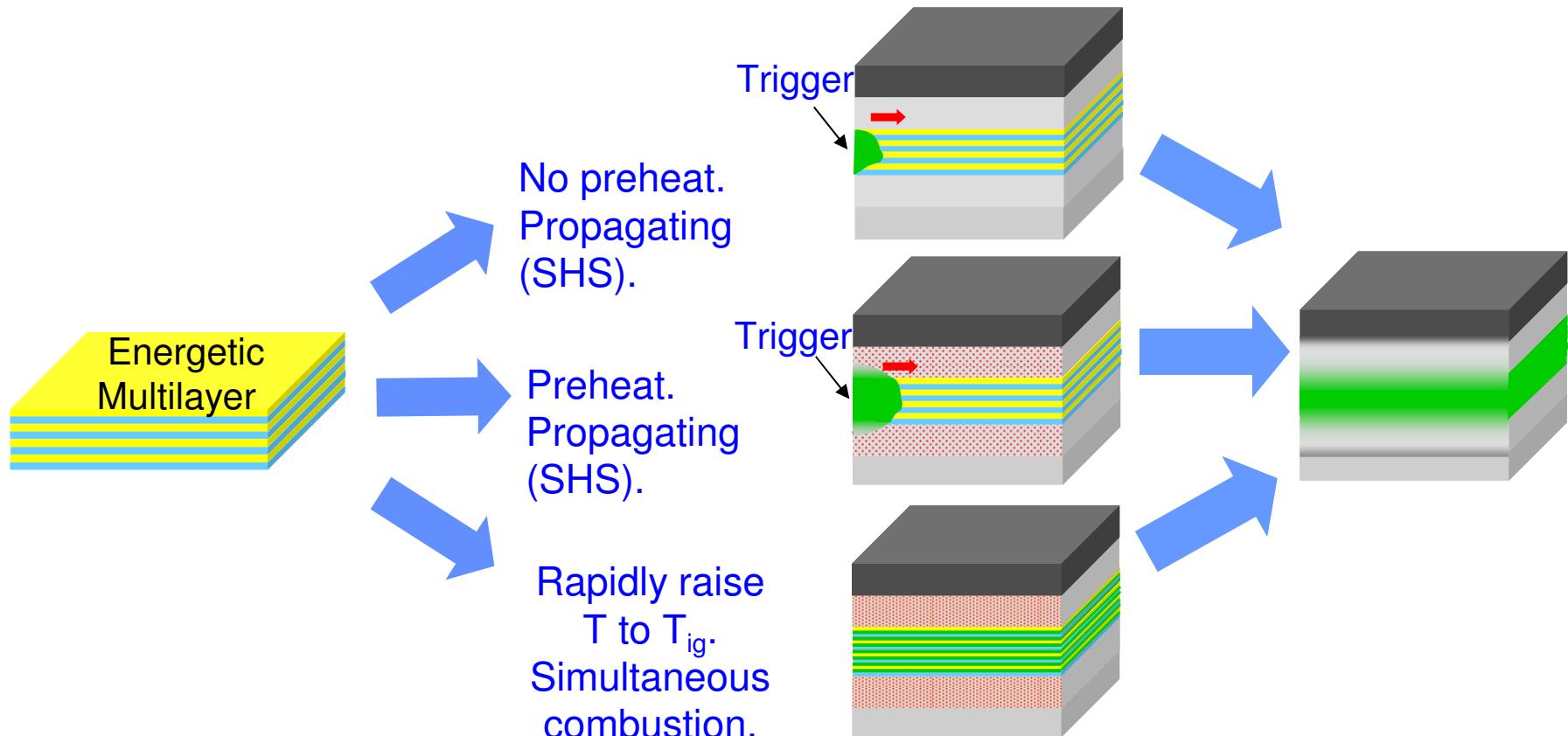
*Sandia National Laboratories
Albuquerque, New Mexico 87185*

6 August 2008



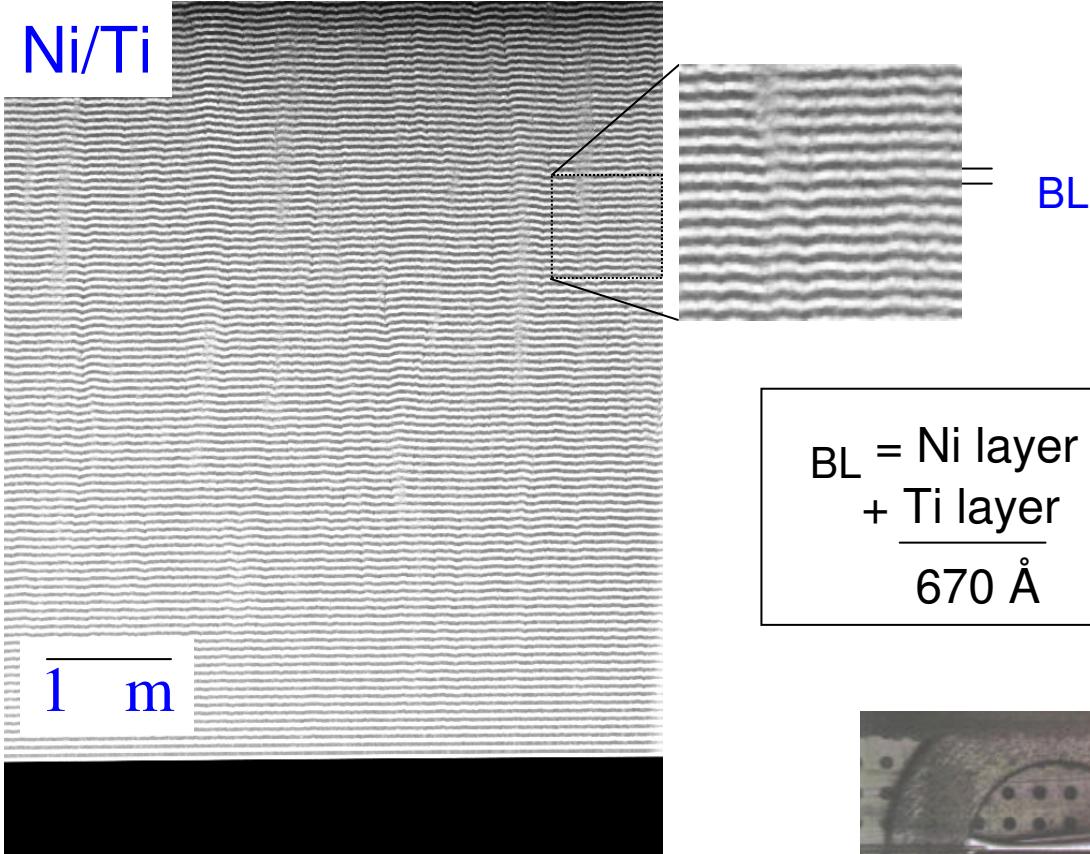
Metal-Metal thin film multilayers store significant energy which can be employed for materials joining

SHS = Self-propagating High-temperature Synthesis
- combustion synthesis



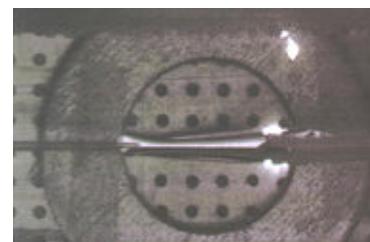


Exothermic thin-film multilayers are heterostructures that consist of two or more species that react.



Typical design:

- Large negative H_f
- Can exhibit high-T combustion synthesis (self-propagating)



NiTi



AlPt

¹ J.A. Floro, J. Vac. Sci. Technol. A, 1986.

² L.A. Clevenger, C.V. Thompson and K.N. Tu, J. App. Phys. 1990.

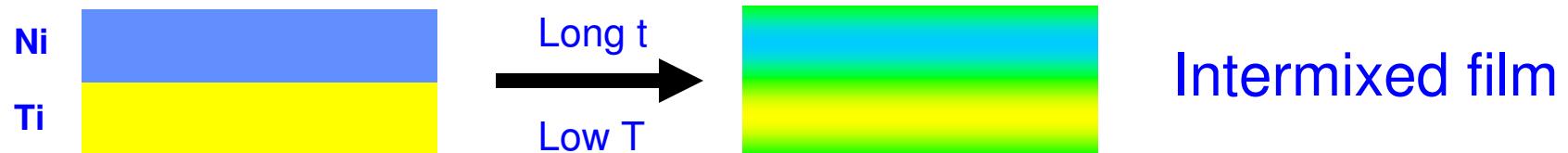
³ T.W. Barbee, T. Weihs, US Patents 5,538,795 5,547,715, 1995.

⁴ C. Suryanarayana, J.J. Moore, R. Radtke, Adv. Mat. and Proc. (2001).



We desired to evaluate not the fast Rx during SHS, but the slower “intermixing” Rx for shelf-life prediction

Slow diffusion of reactants at relatively low temperature (T) over a long time (t) could significantly reduce the stored energy for SHS



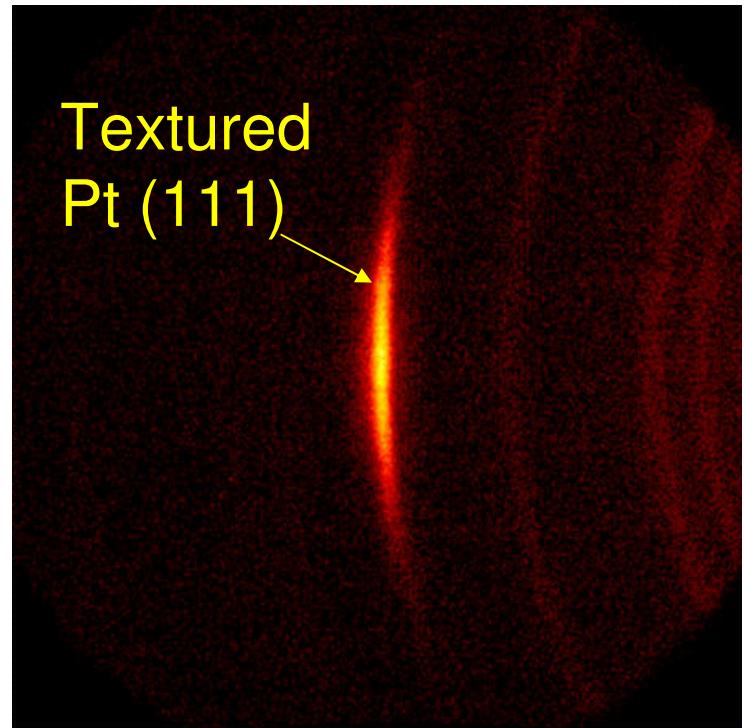
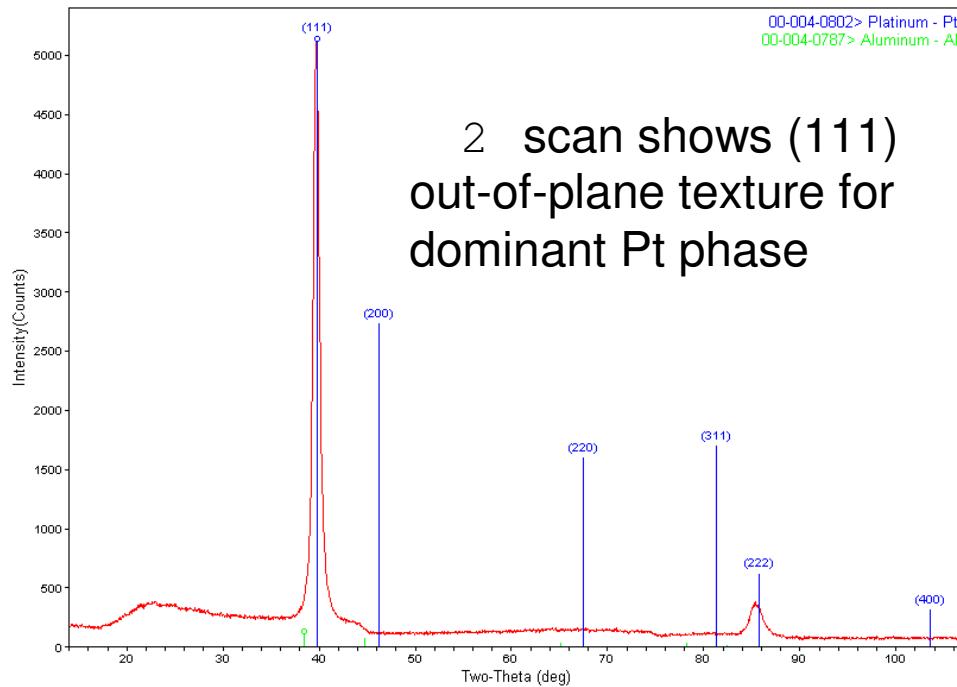
Our approach:

- monitor one film constituent as a $f_n(t)$ at various temperature values.
- assume pseudo-first-order behavior for Rx.
- determine rate constants for decay of Intensity of reactant as $F_n(T)$.
- calculate activation energy for intermixing Rx by Arrhenius relationship.



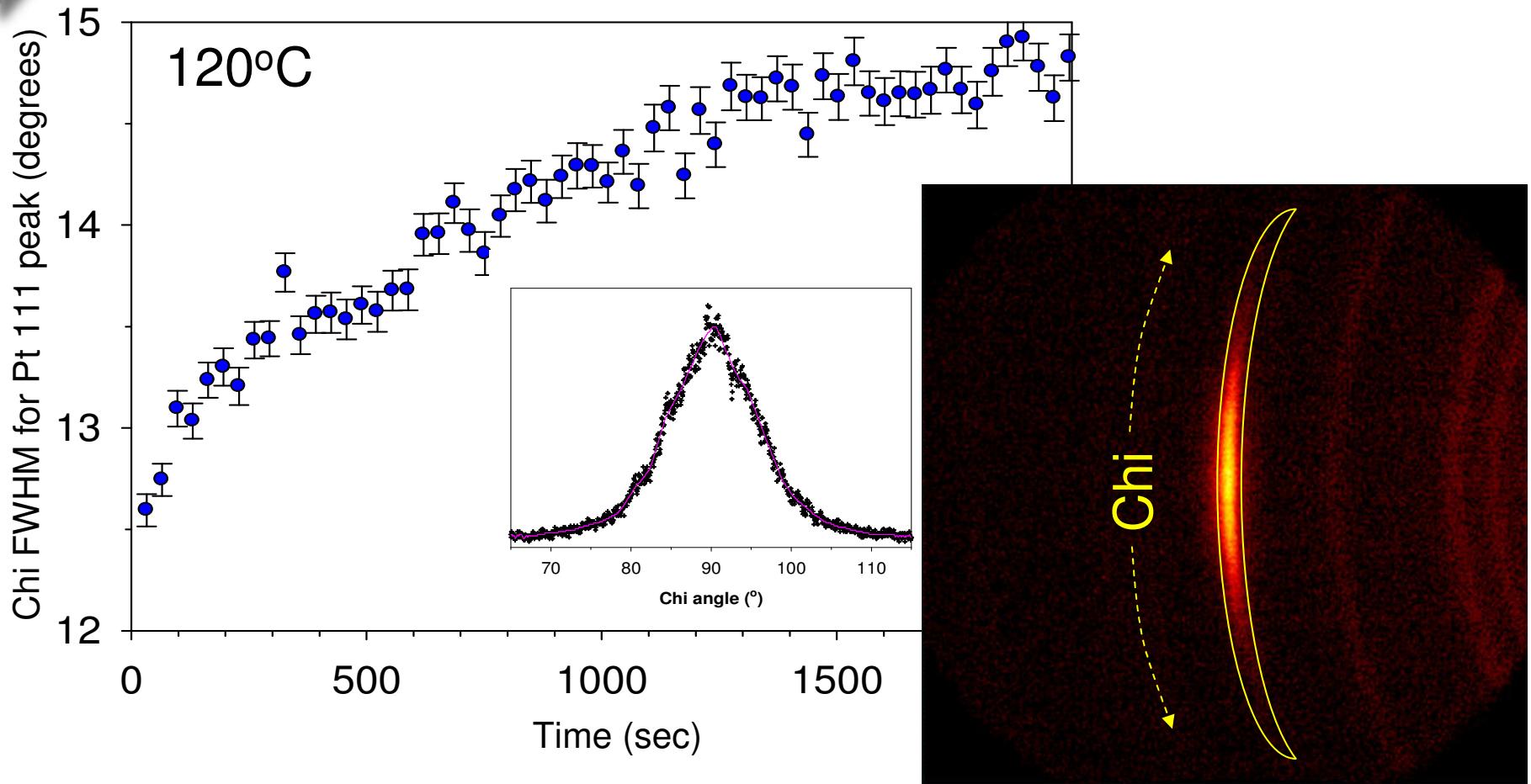
Problem: Multilayer films are often textured. What if texture decreases as sample reacts?

If we measure standard 2θ scans we could be assigning intensity loss from peak assuming loss of constituent concentration and not decay of texture.





Integration along Chi indicates Pt (111) peak FWHM is increasing during intermixing Rx



To account for change in texture during Rx we integrate intensity as a window of 2° and χ



Metal-Metal multilayer films were made using an in-house sputter system.

- Films were deposited by direct-current sputtering
 - cryopumped vacuum system (Unifilm, Boulder CO)
 - base pressure = 8×10^{-8} Torr
 - Argon sputtering gas (10 mTorr)
- high purity elemental targets employed
 - Al (99.995%), Pt (99.95%)
 - Ni (99.99%), Ti (99.99%)
 - Co (99.99%), Al (99.995%)
- Deposited on 0.5mm thick fused Silica substrates
 - Substrate temperature < 50°C



Data collection employed a Bruker D8 system equipped with a Anton-Paar stage

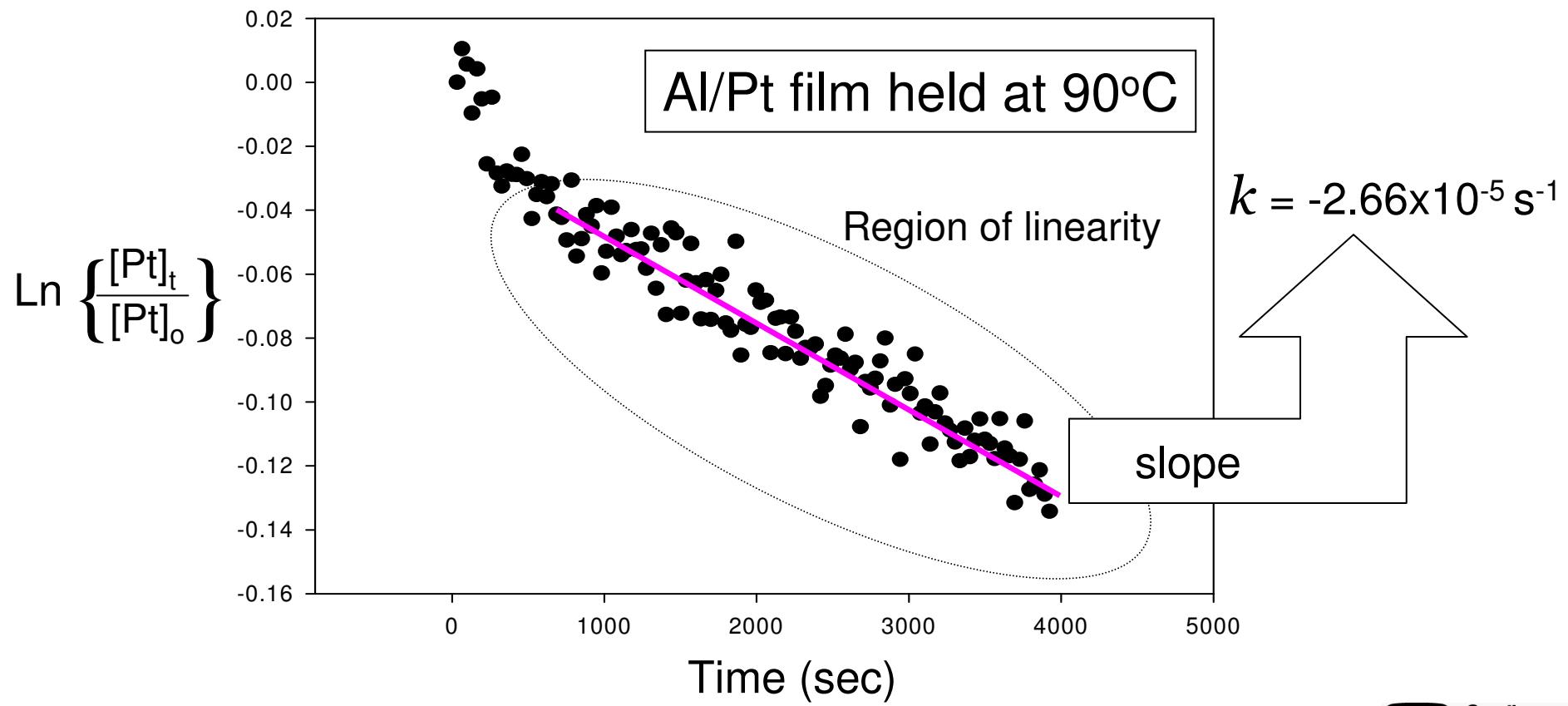


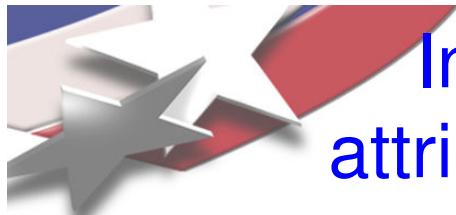
- Temperature calibrated via alumina thermal expansion
- Films heated 10°C/min to various hold temperatures
 - Vacuum ($\sim 10^{-2}$ Torr)
- Data collected using Hi-Star area detector
 - 120 frames @ 30 sec/frame
 - 1 hr total collection time/film
 - 1 mm incident beam snout
- Data integrated in GADDS
- Peak profile fitting performed using JADE 8.5



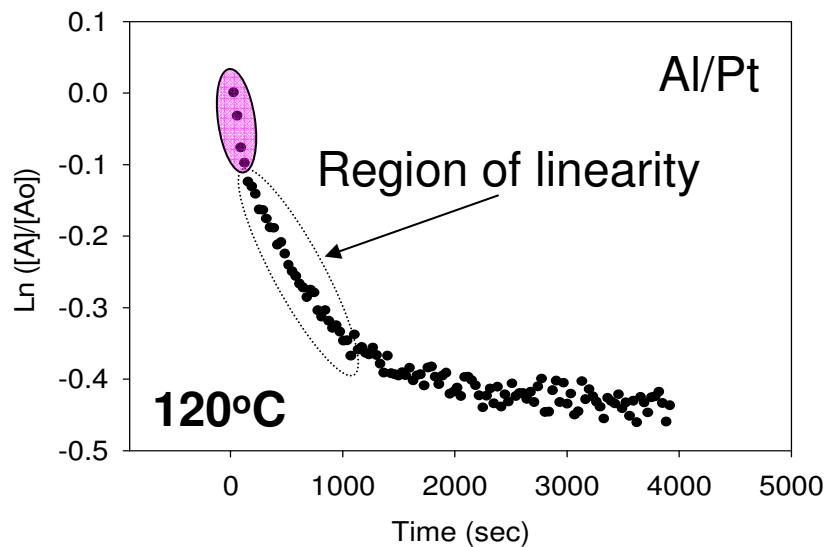
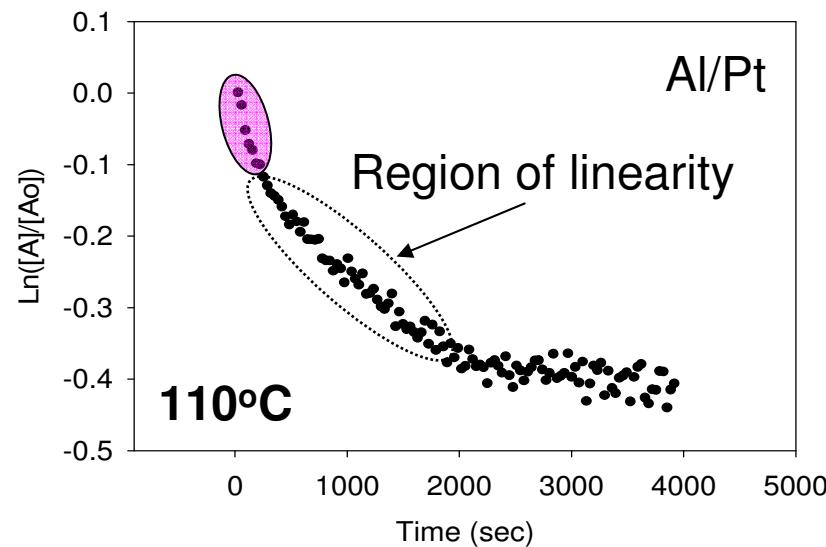
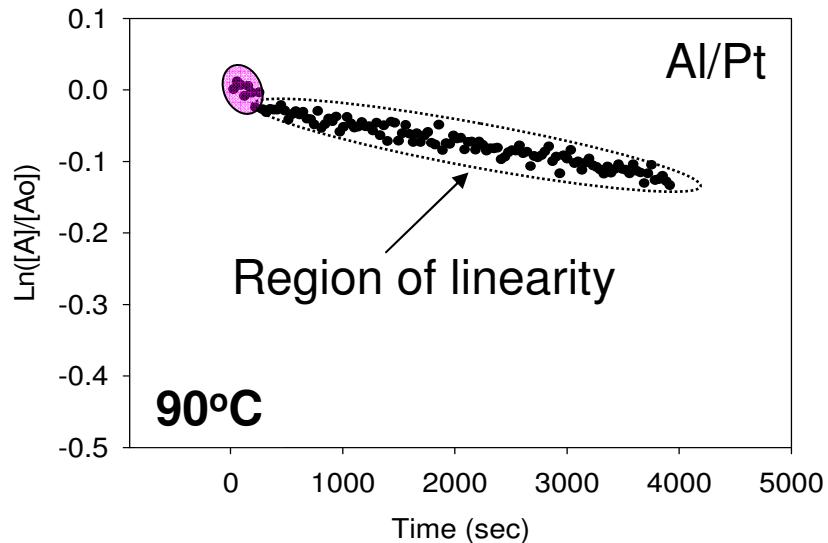
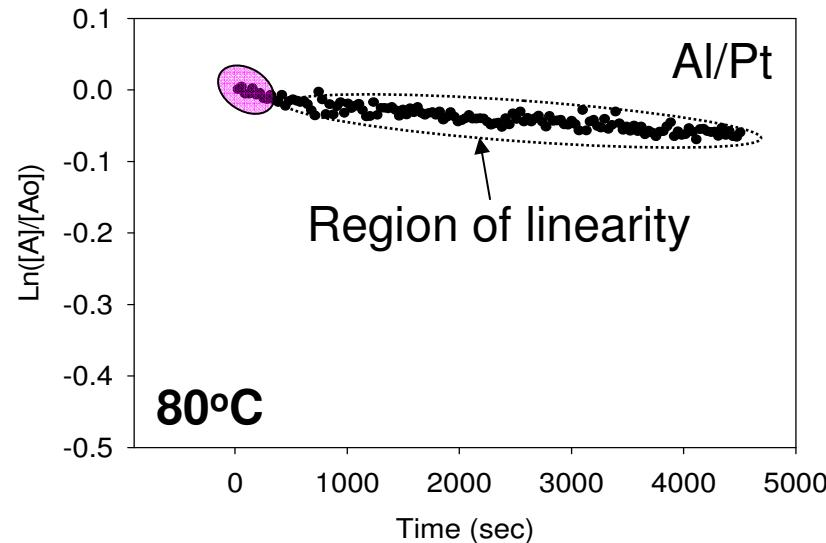
To generate a rate constant for a given (T) we plot the natural log of concentration vs. time

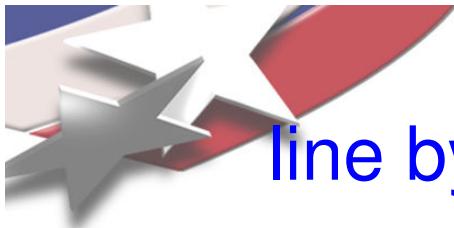
We assume that the intensity of the Pt (111) is \propto to $[Pt]$



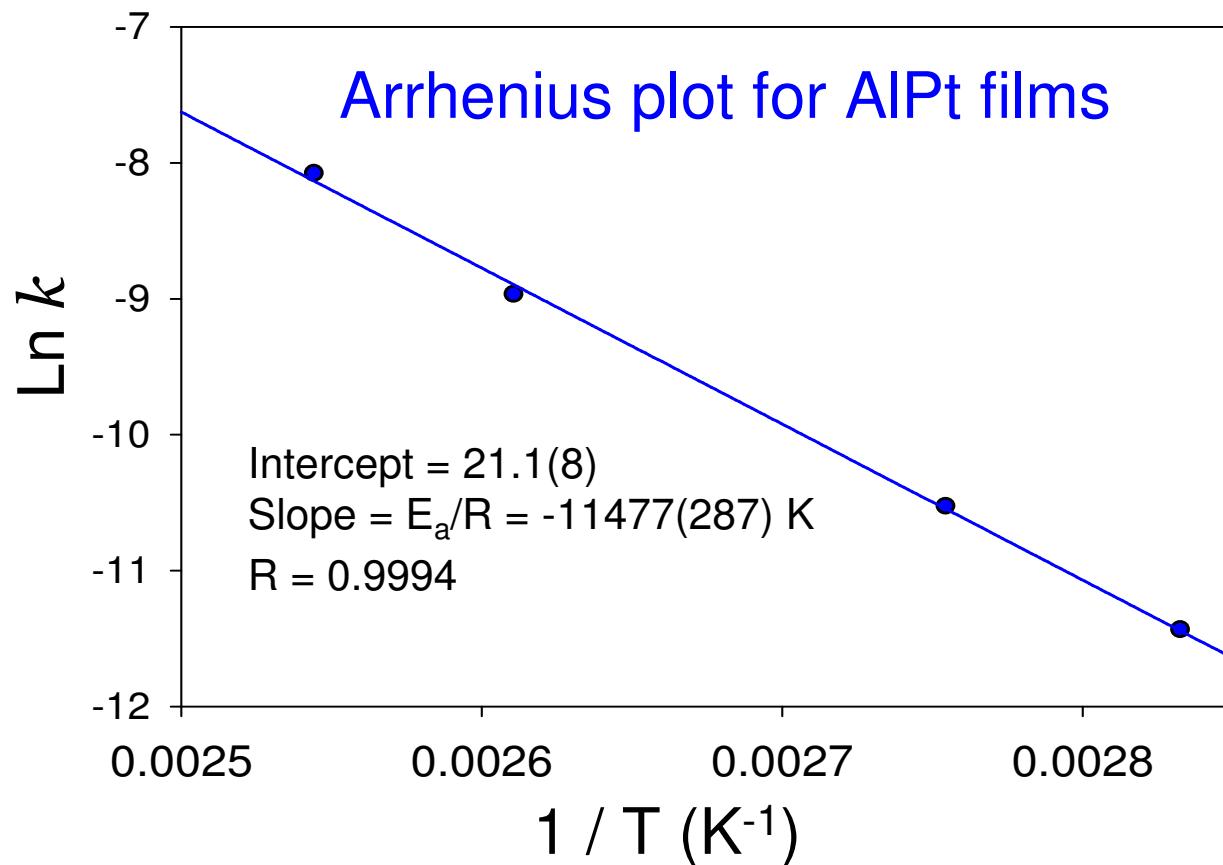


Increased reaction rate in first few minutes attributed to temperature overshoot of controller





Plot of $\ln(\text{rate constants})$ vs. $1/T$ generates line by which activation energy may be calculated



$$\text{AlPt } E_a = 1.1477 \times 10^4 \text{ (K)} * 8.314 \text{ (J K}^{-1}\text{mol}^{-1}) = 95.4 \pm 0.2 \text{ kJ/mol}$$

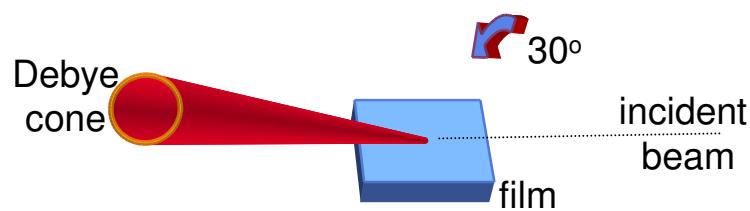
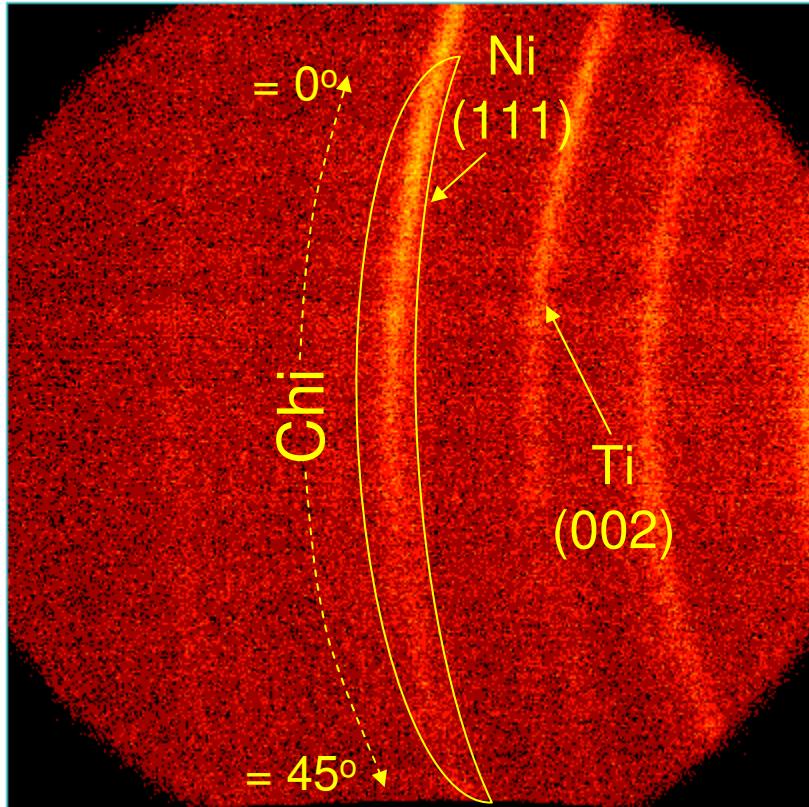


We have performed the same analysis for NiTi and CoAl Metal-Metal Multilayer films

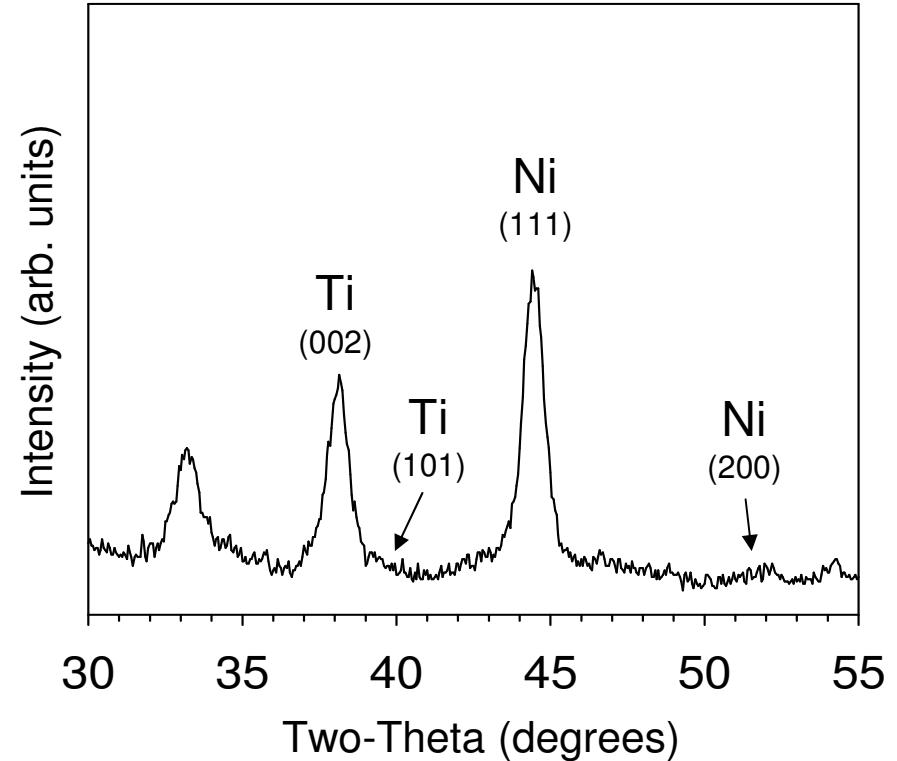
- Lower scattering from lighter elements
- Needed to improve signal from film layers
- Bilayer thickness for Ni/Ti and Co/Al increased to 500 Å
- Increased total thickness for Ni/Ti and Co/Al to ~1 m (20 Bilayers)
- Films tended to be less oriented



Ni/Ti shows out-of-plane texture of Ni (111) and Ti (002) but with larger variability in Chi angle



NNSA
National Nuclear Security Administration

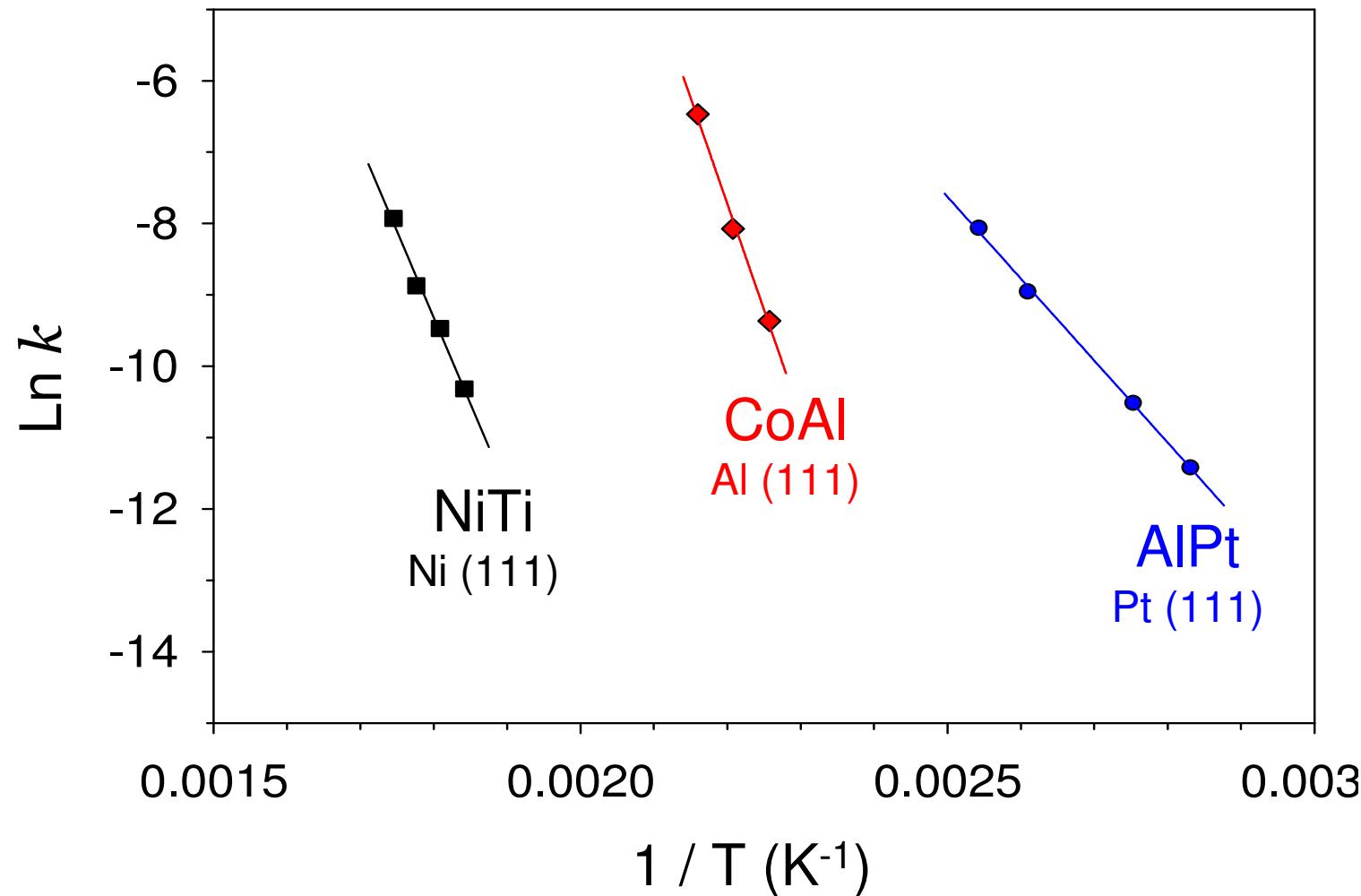


Film tilted 30° in Chi angle from normal to get at least **half** of intensity distributed along Chi

 Sandia
National
Laboratories



Ni/Ti and Co/Al films show higher E_a for intermixing as compared to Al/Pt





Analysis of reaction results for different film systems shows Al/Pt is most susceptible to the intermixing behavior

Film	Bilayer Thickness (Å)	Number Bilayers	Total Thickness (m)	Observed <i>hkl</i>	E_a (kJ/mol)	Rx Temp. range (°C)
Al/Pt	400	5	0.20	Pt (111)	95.4(2)	80-120
Co/Al	500	20	1.00	Al (111)	247(19)	170-190
Ni/Ti	522	20	1.04	Ni (111)	201(13)	270-300



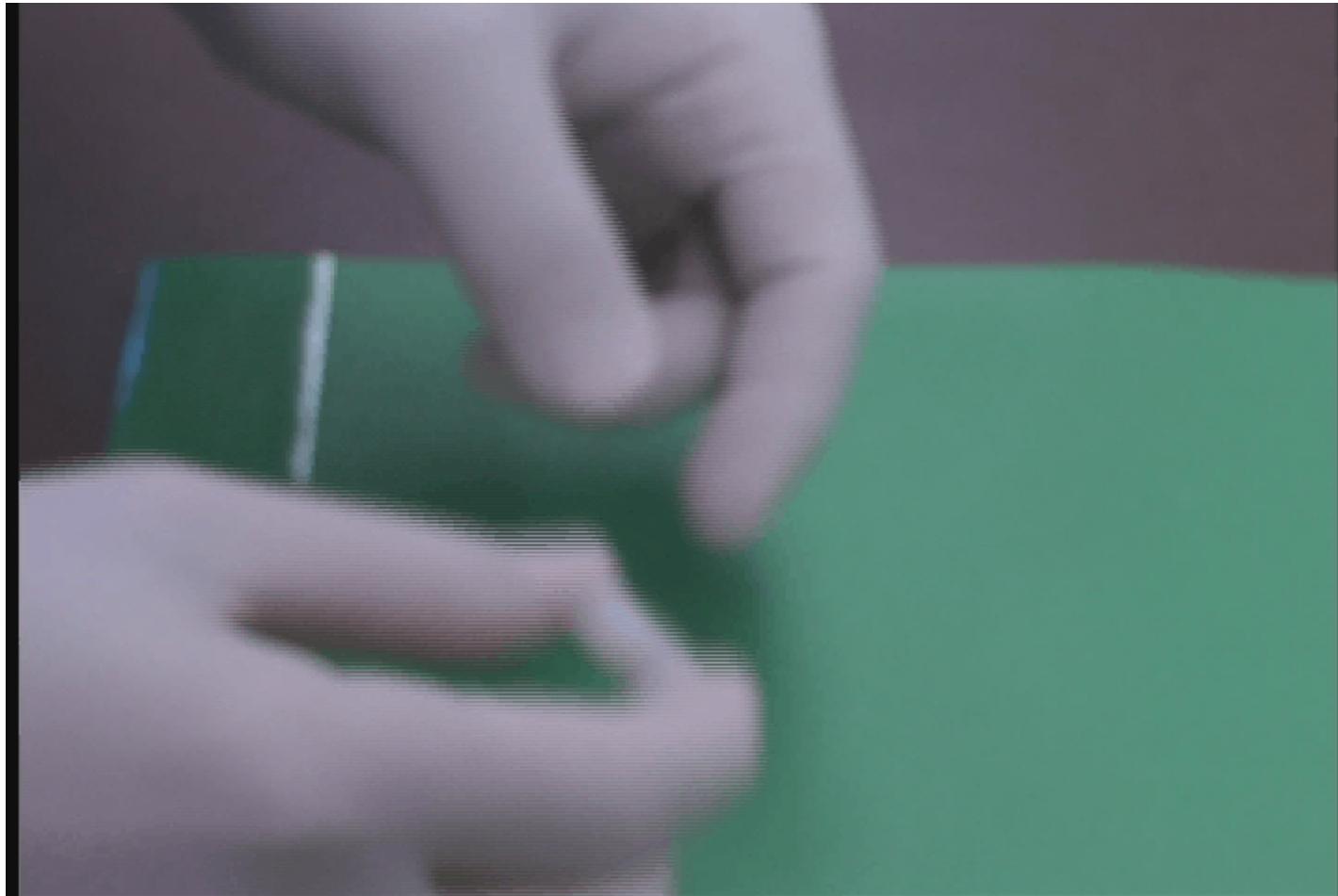
Conclusions

- Use of a 2D area detector facilitates collection of Rx kinetics data from textured films.
- Reactions can be monitored for both texture decay and intensity decay simultaneously.
- Al/Pt films show more susceptibility to intermixing reaction than Co/Al or Ni/Ti film systems.



Fun movie

Joining plastic via Ni/Al Exothermic Metal-Metal Multilayer films





Acknowledgments

- **Malisu Bai (Co. School of Mines) for fun movie.**
- **Luke Brewer and Michael Rye for FIB and TEM data.**
- Sandia is a multiprogram laboratory operated by Sandia Corporation, a Lockheed Martin Company, for the United States Department of Energy's National Nuclear Security Administration under contract DE-AC04-94AL85000.